Volume 100, Number 6, November–December 1995
Journal of Research of the National Institute of Standards and Technology

Subject Index to Volume 100

Numbers in parenthesis in italic type after the volume number are the issue numbers

No. 1 January–February
No. 2 March–April
No. 3 May–June
No. 4 July–August
No. 5 September–October
No. 6 November–December

A

absorber modelling ..... 257(*3*)
absorbing walls ..... 257(*3*)
absorption ..... 373(*4*)
ac quantum Hall effect ..... 677(*6*)
adsorbed water ..... 75(*1*)
algorithm testing service ..... 563(*5*)
alpha counting ..... 1(*1*)
anechoic chambers ..... 257(*3*)
aperture ..... 277(*3*), 591(*5*)
application portability profile ..... 83(*1*)
area ..... 277(*3*)
argon ..... 373(*4*)
argon discharge ..... 473(*4*)
argon-oxygen plasmas ..... 383(*4*)
artificial intelligence ..... 67(*1*)
asymptotic expansion ..... 61(*1*)
atomic weights ..... 285(*3*)
automated testing ..... 699(*6*)

B

Baldrige Award ..... 287(*3*)
benzoic acid ..... 521(*5*)
blackbody ..... 591(*5*)
boundary value problem ..... 61(*1*)
boundary value problems ..... 661(*6*)
breakdown of dissipationless state ..... 529(*5*)

C

calibration ..... 37(*1*), 629(*6*)
calibration uncertainty ..... 543(*5*)
candela ..... 227(*3*)
carbon ..... 285(*3*), 641(*6*)
cavity ..... 591(*5*)
ceramic powder ..... 51(*1*)
charge-coupled device camera ..... 241(*3*)
charge distributions ..... 529(*5*)
chemical vapor deposition ..... 43(*1*)
chronoamperometry ..... 61(*1*)
circuit technology ..... 711(*6*)
closed system ..... 43(*1*)
cobalt ..... 641(*6*)
collocation ..... 661(6)
communication systems ..... 71(*1*)
composite ..... 641(*6*)
computational metrology ..... 563(*5*)
computer assurance ..... 601(*5*)
computer security ..... 301(*3*)
computing machinery ..... 67(*1*)
conductivity ..... 119(2)
conformance testing ..... 699(*6*)
contaminant water ..... 75(*1*)
coordinate measurement systems ..... 563(*5*)
Coulomb solids ..... 449(*4*)
critical systems ..... 601(*5*)
cryogenic ..... 119(2)
cryogenic current comparator ..... 677(*6*)
current ..... 341(*4*)
current distributions ..... 529(*5*)

D

dc quantum Hall effect ..... 677(*6*)
density ..... 51(*1*)
diamond films ..... 43(*1*)
diamond indenter ..... 543(*5*)
dielectric constant ..... 521(*5*)
Digital Signature Standard ..... 301(*3*)
dimensional metrology ..... 563(*5*)
discharge ..... 341(*4*), 373(*4*), 401(*4*), 441(*4*), 449(*4*)
discontinuous Bessel integral ..... 61(*1*)
discotic phase ..... 173(2)
distributed systems ..... 699(*6*)
drying shrinkage ..... 575(*5*)
dynamic laser light scattering ..... 449(*4*)

E

E-PERM® ..... 629(*6*)
electret ..... 629(*6*)

electric fields ..... 269(3), 373(4)
electrolytic conductivity ..... 521(5)
electron density ..... 401(4)
EMC modelling ..... 257(3)
emissivity ..... 591(5)
energy levels ..... 687(6)
environment ..... 629(6)
environmental issues ..... 575(5)
equivalent electrical circuit ..... 677(6)
etch depth ..... 441(4)
etch rate ..... 441(4)
etching ..... 441(4)
extended set-retarders ..... 575(5)

F

filter certification ..... 241(3)
Flory-Huggins ..... 173(2)
fluid model ..... 463(4)

G

Gaseous Electronics Conference ..... 327(4), 341(4), 353(4), 373(4), 401(4), 415(4), 427(4), 441(4), 449(4), 463(4), 473(4), 495(4)
geometric fitting ..... 563(5)
graphite ..... 641(6)

H

helium ..... 373(4)
high density plasmas ..... 427(4)
hybrid model ..... 463(4)
hydrogen ..... 285(3)

I

impedance ..... 341(4)
inductively coupled plasmas ..... 427(4)
information management ..... 67(1)
information technology ..... 83(1), 301(3)
integrating spheres ..... 37(1)
ion bombardment ..... 383(4)
ion energy analyzers ..... 383(4)
ion kinetic-energy distributions ..... 383(4)
ionization chamber ..... 629(6)
iridium (Ir VIII) ..... 687(6)
isotopic ratios ..... 285(3)

K

knowledge management ..... 67(1)

L

Langmuir probes ..... 415(4), 427(4)
Laplace transform ..... 61(1)
large-area apertures ..... 37(1)
laser-induced fluorescence ..... 373(4)
laser light scattering ..... 449(4)
layered silicates ..... 173(2)
lead-205 ..... 1(1)
liquid crystals ..... 173(2)
liquid scintillation (LS) ..... 1(1)
logarithmic charge-redistribution potential ..... 529(5)
low conductivity standard ..... 521(5)
lumen ..... 227(3)
luminous flux ..... 227(3)
luminous intensity ..... 227(3)

M

magnetic permeability ..... 209(3)
magnetic susceptibility ..... 209(3)
mass metrology ..... 209(3)
mass spectrometry ..... 383(4)
mass standards ..... 209(3)
measurement ..... 277(3), 629(6)
measurement uncertainty ..... 563(5)
mechanical tolerancing ..... 563(5)
microelectronics ..... 711(6)
microform ..... 543(5)
microwave diagnostics ..... 401(4)
microwave interferometer ..... 401(4)

N

nonaqueous solvent ..... 521(5)

O

Onsager limiting law ..... 521(5)
open system environment ..... 83(1), 699(6)
optical emission ..... 353(4)
optical filters ..... 241(3)
orthogonal distance regression ..... 563(5)
osmium (Os VII) ..... 687(6)
oxygen ..... 285(3)

P

parabolic confining potential ..... 529(5)
parallel plate ..... 373(4)
particle size ..... 51(1)
particle traps ..... 449(4)
particles ..... 449(4)
photometer ..... 227(3)
plasma ..... 341(4), 353(4), 401(4), 495(4)
plasma diagnostic ..... 415(4)
plasma modeling ..... 473(4)
plasma processing ..... 373(4), 449(4), 463(4), 473(4)
plasma reactor ..... 327(4)
plate-rod transition ..... 173(2)
Poisson's equation ..... 661(6)
polonium-209 ..... 1(1)
potassium chloride ..... 521(5)
potential distributions ..... 529(5)

Q

quality programs ..... 287(3)
quantized dissipation ..... 269(3)
quantized Hall resistance ..... 677(6)
quantized voltage states ..... 269(3)
quantum Hall effect ..... 269(3), 529(5)
quasi-elastic inter-Landau level scattering ..... 269(3)

R

radiation ..... 591(5)
radio frequency ..... 327(4), 341(4), 373(4), 441(4), 495(4)
radio-frequency discharges ..... 383(4)
radioactivity ..... 1(1)
radiometry ..... 37(1), 591(5)
radium-226 ..... 629(6)
radon-222 ..... 629(6)
Raman ..... 43(1)
reactive ion etching ..... 441(4)
ready mixed concrete ..... 575(5)
recycling ..... 575(5)
reference cell ..... 327(4), 353(4), 463(4), 473(4)
reflectance ..... 591(5)
resistivity ..... 119(2)
returned plastic concrete ..... 575(5)
rf discharges ..... 353(4), 463(4), 473(4)
Rockwell hardness ..... 543(5)
rod-rod transition ..... 173(2)

S

scanning electron microscopy ..... 43(1)
semiconductors ..... 661(6), 711(6)
setting time ..... 575(5)
silver ..... 119(2)
software uncertainty ..... 563(5)
spatial mapping ..... 37(1)
specific surface area ..... 51(1)
spectra ..... 687(6)
spectral radiance ..... 37(1)
spectrophotometry ..... 37(1), 241(3)
spectroscopy ..... 353(4)
stabilizing admixtures ..... 575(5)
standard reference materials ..... 241(3)
standards ..... 1(1), 601(5), 629(6), 699(6)
superconductor ..... 119(2)
susceptometer ..... 209(3)

T

telecommunications ..... 71(1)
temperature ..... 591(5)
temporal dependence ..... 401(4)
terahertz physics ..... 717(6)
thermometer ..... 591(5)
total flux ..... 227(3)
transmittance homogeneity ..... 241(3)
transport ..... 119(2)
tungsten ..... 641(6)
two-dimensional electron gas ..... 269(3), 529(5), 677(6)
two-dimensional simulation ..... 473(4)

V

vacuum environments ..... 75(1)
voltage ..... 341(4), 495(4)

W

wash water ..... 575(5)
water bath ..... 591(5)
water vapor ..... 75(1)
wireless communications ..... 71(1)
wireless standards ..... 71(1)

X

x-ray diffraction ..... 43(1)

Volume 100, Number 6, November–December 1995
Journal of Research of the National Institute of Standards and Technology

Author Index to Volume 100

Numbers in parenthesis in italic type after the volume number are the issue numbers

No. 1 January–February
No. 2 March–April
No. 3 May–June
No. 4 July–August
No. 5 September–October
No. 6 November–December

A

Anderson, H. M.

Dusty Plasma Studies in the Gaseous Electronics Conference RF Reference Cell. Anderson, H. M., and Radovanov, S. B. **100**(*4*), 449 (1995).

Antonishek, T.

Federal Wireless Users' Forum Workshop. Ruhl, M. K., and Antonishek, T. **100**(*1*), 71 (1995).

Aragon, B. P.

An Inductively Coupled Plasma Source for the Gaseous Electronics Conference RF Reference Cell. Miller, P. A., Hebner, G. A., Greenberg, K. E., Pochan, P. D., and Aragon, B. P. **100**(*4*), 427 (1995).

B

Berezansky, P. A.

Low Electrolytic Conductivity Standards. Wu, Y. C., and Berezansky, P. A. **100**(*5*), 521 (1995).

Brake, M. L.

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

Buie, M. J.

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

C

Cage, M. E.

Using Quantized Breakdown Voltage Signals to Determine the Maximum Electric Fields in a Quantum Hall Effect Sample. Cage, M. E., and Lavine, C. F. **100**(*3*), 269 (1995).

Potential and Current Distributions Calculated Across a Quantum Hall Effect Sample at Low and High Currents. Cage, M. E., and Lavine, C. F. **100**(*5*), 529 (1995).

Precision Tests of a Quantum Hall Effect Device DC Equivalent Circuit Using Double-Series and Triple-Series Connections. Jeffery, A., Elmquist, R. E., and Cage, M. E. **100**(*6*), 677 (1995).

Chapman, R. E.

Quest for Excellence VII. Frank, C., and Chapman, R. E. **100**(*3*), 287 (1995).

Collé, R.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

Calibration of Electret-Based Integral Radon Monitors Using NIST Polyethylene-Encapsulated ^{226}Ra/^{222}Rn Emanation (PERE) Standards. Collé, R., Kotrappa, P., and Hutchinson, J. M. R. **100**(*6*), 629 (1995).

Coplen, T. B.

New IUPAC Guidelines for the Reporting of Stable Hydrogen, Carbon, and Oxygen Isotope-Ratio Data. Coplen, T. B. **100**(*3*), 285 (1995).

Coursey, B. M.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

D

Danner, B. P.

COMPASS '95 Tenth Annual Conference on Computer Assurance. Danner, B. P., Ippolito, L. M., and Wallace, D. R. **100**(*5*), 601 (1995).

Datla, R.

Metrology Issues in Terahertz Physics and Technology. Datla, R., Grossman, E., and Hobish, M. K. **100**(*6*), 717 (1995).

Davis, R. S.

Determining the Magnetic Properties of 1 kg Mass Standards. Davis, R. S. **100**(*3*), 209 (1995).

Dezsi, G.

High Accuracy Measurement of Aperture Area Relative to a Standard Known Aperture. Fowler, J. B., and Dezsi, G. **100**(*3*), 277 (1995).

Di Marzio, E. A.

Mixing Plate-Like and Rod-Like Molecules With Solvent: A Test of Flory-Huggins Lattice Statistics. Di Marzio, E. A., Yang, A. J.-M., and Glotzer, S. C. **100**(*2*), 173 (1995).

Durst, R. A.

On the Applications of Discontinuous Bessel Integrals to Chronoamperometry. Yap, W. T., and Durst, R. A. **100**(*1*), 61 (1995).

E

Economou, D. J.

Two-Dimensional Self-Consistent Radio Frequency Plasma Simulations Relevant to the Gaseous Electronics Conference RF Reference Cell. Lymberopoulos, D. P., and Economou, D. J. **100**(*4*), 473 (1995).

Elmquist, R. E.

Precision Tests of a Quantum Hall Effect Device DC Equivalent Circuit Using Double-Series and Triple-Series Connections. Jeffery, A., Elmquist, R. E., and Cage, M. E. **100**(*6*), 677 (1995).

F

Farabaugh, E. N.

Deposition of Diamond Films in a Closed Hot Filament CVD System. Guan-Ren, L., Farabaugh, E. N., Feldman, A., and Robins, L. H. **100**(*1*), 43 (1995).

Feldman, A.

Deposition of Diamond Films in a Closed Hot Filament CVD System. Guan-Ren, L., Farabaugh, E. N., Feldman, A., and Robins, L. H. **100**(*1*), 43 (1995).

Fickett, F. R.

Low-Temperature Properties of Silver. Smith, D. R., and Fickett, F. R. **100**(*2*), 119 (1995).

Fong, E.

Third International Conference on Information and Knowledge Management (CIKM-94). Fong, E., Hurwitz, S., and Yesha, Y. **100**(*1*), 67 (1995).

Fowler, J. B.

High Accuracy Measurement of Aperture Area Relative to a Standard Known Aperture. Fowler, J. B., and Dezsi, G. **100**(*3*), 277 (1995).

A Third Generation Water Bath Based Blackbody Source. Fowler, J. B. **100**(*5*), 591 (1995).

Frank, C.

Quest for Excellence VII. Frank, C., and Chapman, R. E. **100**(*3*), 287 (1995).

G

Gallagher, J. W.

Forty-Seventh Annual Gaseous Electronics Conference. Van Brunt, R. J., and Gallagher, J. W. **100**(*4*), 495 (1995).

Gilbert, D.

17th National Computer Security Conference. Gilbert, D. **100**(*3*), 301 (1995).

Glotzer, S. C.

Mixing Plate-Like and Rod-Like Molecules With Solvent: A Test of Flory-Huggins Lattice Statistics. Di Marzio, E. A., Yang, A. J.-M., and Glotzer, S. C. **100**(*2*), 173 (1995).

Govindan, T. R.

One-Dimensional Modeling Studies of the Gaseous Electronics Conference RF Reference Cell. Govindan, T. R., and Meyyappan, M. **100**(*4*), 463 (1995).

Gray, M. M.

Application Portability Profile and Open System Environment User's Forum. Hungate, J. I., Gray, M. M., and Liburdy, K. A. **100**(*6*), 699 (1995).

Greenberg, K. E.

The Gaseous Electronics Conference RF Reference Cell—An Introduction. Olthoff, J. K., and Greenberg, K. E. **100**(*4*), 327 (1995).

Optical Diagnostics in the Gaseous Electronics Conference RF Reference Cell. Hebner, G. A., and Greenberg, K. E. **100**(*4*), 373 (1995).

An Inductively Coupled Plasma Source for the Gaseous Electronics Conference RF Reference Cell. Miller, P. A., Hebner, G. A., Greenberg, K. E., Pochan, P. D., and Aragon, B. P. **100**(*4*), 427 (1995).

Grossman, E.

Metrology Issues in Terahertz Physics and Technology. Datla, R., Grossman, F., and Hobish, M. K. **100**(*6*), 717 (1995).

Guan-Ren, L.

Deposition of Diamond Films in a Closed Hot Filament CVD System. Guan-Ren, L., Farabaugh, E. N., Feldman, A., and Robins, L. H. **100**(*1*), 43 (1995).

Guthrie, W. F.

A Study on the Reuse of Plastic Concrete Using Extended Set-Retarding Admixtures. Lobo, C., Guthrie, W. F., and Kacker, R. **100**(*5*), 575 (1995).

H

Hebner, G. A.

Optical Diagnostics in the Gaseous Electronics Conference RF Reference Cell. Hebner, G. A., and Greenberg, K. E. **100**(*4*), 373 (1995).

An Inductively Coupled Plasma Source for the Gaseous Electronics Conference RF Reference Cell. Miller, P. A., Hebner, G. A., Greenberg, K. E., Pochan, P. D., and Aragon, B. P. **100**(*4*), 427 (1995).

Hobish, M. K.

Metrology Issues in Terahertz Physics and Technology. Datla, R., Grossman, E., and Hobish, M. K. **100**(*6*), 717 (1995).

Hodge, P. A.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

Hopkins, M. B.

Langmuir Probe Measurements in the Gaseous Electronics Conference RF Reference Cell. Hopkins, M. B. **100**(*4*), 415 (1995).

Hopp, T. H.

Performance Measures for Geometric Fitting in the NIST Algorithm Testing and Evaluation Program for Coordinate Measurement Systems. Hopp, T. H., and Levenson, M. S. **100**(*5*), 563 (1995).

Hsu, S. M.

Variances in the Measurement of Ceramic Powder Properties. Munro, R. G., Malghan, S. G., and Hsu, S. M. **100**(*1*), 51 (1995).

Hungate, J. I.

Application Portability Profile and Open System Environment Users' Forum. Hungate, J. **100**(*1*), 83 (1995).

Application Portability Profile and Open System Environment User's Forum. Hungate, J. I., Gray, M. M., and Liburdy, K. A. **100**(*6*), 699 (1995).

Hurwitz, S.

Third International Conference on Information and Knowledge Management (CIKM-94). Fong, E., Hurwitz, S., and Yesha, Y. **100**(*1*), 67 (1995).

Hutchinson, J. M. R.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

Calibration of Electret-Based Integral Radon Monitors Using NIST Polyethylene-Encapsulated ^{226}Ra/^{222}Rn Emanation (PERE) Standards. Collé, R., Kotrappa, P., and Hutchinson, J. M. R. **100**(*6*), 629 (1995).

I

Ippolito, L. M.

COMPASS '95 Tenth Annual Conference on Computer Assurance. Danner, B. P., Ippolito, L. M., and Wallace, D. R. **100**(*5*), 601 (1995).

J

Jeffery, A.

Precision Tests of a Quantum Hall Effect Device DC Equivalent Circuit Using Double-Series and Triple-Series Connections. Jeffery, A., Elmquist, R. E., and Cage, M. E. **100**(*6*), 677 (1995).

Joshi, Y. N.

Analysis of the $(5d^2{+}5d6s) - 5d6p$ Transition Arrays of Os VII and Ir VIII, and the $6s\ ^2S - 6p\ ^2P$ Transitions of Ir IX. van het Hof, G. J., Joshi, Y. N., Wyart, J. F., and Sugar, J. **100**(*6*), 687 (1995).

K

Kacker, R.

A Study on the Reuse of Plastic Concrete Using Extended Set-Retarding Admixtures. Lobo, C., Guthrie, W. F., and Kacker, R. **100**(*5*), 575 (1995).

Kotrappa, P.

Calibration of Electret-Based Integral Radon Monitors Using NIST Polyethylene-Encapsulated ^{226}Ra/^{222}Rn Emanation (PERE) Standards. Collé, R., Kotrappa, P., and Hutchinson, J. M. R. **100**(*6*), 629 (1995).

L

Lavine, C. F.

Using Quantized Breakdown Voltage Signals to Determine the Maximum Electric Fields in a Quantum Hall Effect Sample. Cage, M. E., and Lavine, C. F. **100**(*3*), 269 (1995).

Potential and Current Distributions Calculated Across a Quantum Hall Effect Sample at Low and High Currents. Cage, M. E., and Lavine, C. F. **100**(*5*), 529 (1995).

Levenson, M. S.

Performance Measures for Geometric Fitting in the NIST Algorithm Testing and Evaluation Program for Coordinate Measurement Systems. Hopp, T. H., and Levenson, M. S. **100**(*5*), 563 (1995).

Liburdy, K. A.

Application Portability Profile and Open System Environment User's Forum. Hungate, J. I., Gray, M. M., and Liburdy, K. A. **100**(*6*), 699 (1995).

Lin, Z.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

Lobo, C.

A Study on the Reuse of Plastic Concrete Using Extended Set-Retarding Admixtures. Lobo, C., Guthrie, W. F., and Kacker, R. **100**(*6*), 575 (1995).

Looney, J. P.

Workshop on Water: Its Measurement and Control in Vacuum. Tison, S. A., and Looney, J. P. **100**(*1*), 75 (1995).

Lymberopoulos, D. P.

Two-Dimensional Self-Consistent Radio Frequency Plasma Simulations Relevant to the Gaseous Electronics Conference RF Reference Cell. Lymberopoulos, D. P., and Economou, D. J. **100**(*4*), 473 (1995).

M

Malghan, S. G.

Variances in the Measurement of Ceramic Powder Properties. Munro, R. G., Malghan, S. G., and Hsu, S. M. **100**(*1*), 51 (1995).

Marchiando, J. F.

On Using Collocation in Three Dimensions and Solving a Model Semiconductor Problem. Marchiando, J. F. **100**(*6*), 661 (1995).

Meyyappan, M.

One-Dimensional Modeling Studies of the Gaseous Electronics Conference RF Reference Cell. Govindan, T. R., and Meyyappan, M. **100**(*4*), 463 (1995).

Miller, P. A.

An Inductively Coupled Plasma Source for the Gaseous Electronics Conference RF Reference Cell. Miller, P. A., Hebner, G. A., Greenberg, K. E., Pochan, P. D., and Aragon, B. P. **100**(*4*), 427 (1995).

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

Munro, R. G.

Variances in the Measurement of Ceramic Powder Properties. Munro, R. G., Malghan, S. G., and Hsu, S. M. **100**(*1*), 51 (1995).

O

Ohno, Y.

1993 Intercomparison of Photometric Units Maintained at NIST (USA) and PTB (Germany). Ohno, Y., and Sauter, G. **100**(*3*), 227 (1995).

Olthoff, J. K.

The Gaseous Electronics Conference RF Reference Cell—An Introduction. Olthoff, J. K., and Greenberg, K. E. **100**(*4*), 327 (1995).

Studies of Ion Kinetic-Energy Distributions in the Gaseous Electronics Conference RF Reference Cell. Olthoff, J. K., Van Brunt, R. J., and Radovanov, S. B. **100**(*4*), 383 (1995).

Overzet, L. J.

Microwave Diagnostic Results from the Gaseous Electronics Conference RF Reference Cell. Overzet, L. J. **100**(*4*), 401 (1995).

P

Pender, J. T. P.

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

Pochan, P. D.

An Inductively Coupled Plasma Source for the Gaseous Electronics Conference RF Reference Cell. Miller, P. A., Hebner, G. A., Greenberg, K. E., Pochan, P. D., and Aragon, B. P. **100**(*4*), 427 (1995).

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

R

Radovanov, S. B.

Studies of Ion Kinetic-Energy Distributions in the Gaseous Electronics Conference RF Reference Cell. Olthoff, J. K., Van Brunt, R. J., and Radovanov, S. B. **100**(*4*), 383 (1995).

Dusty Plasma Studies in the Gaseous Electronics Conference RF Reference Cell. Anderson, H. M., and Radovanov, S. B. **100**(*4*), 449 (1995).

Randa, J.

Low-Frequency Model for Radio-Frequency Absorbers. Randa, J. **100**(*3*), 257 (1995).

Ricci, A.

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

Roberts, J. R.

Optical Emission Spectroscopy on the Gaseous Electronics Conference RF Reference Cell. Roberts, J. R. **100**(*4*), 353 (1995).

Robins, L. H.

Deposition of Diamond Films in a Closed Hot Filament CVD System. Guan-Ren, L., Farabaugh, E. N., Feldman, A., and Robins, L. H. **100**(*1*), 43 (1995).

Rudder, F. F., Jr.

Microform Calibration Uncertainties of Rockwell Diamond Indenters. Song, J. F., Rudder, F. F., Jr., Vorburger, T. V., and Smith, J. H. **100**(*5*), 543 (1995).

Ruhl, M. K.

Federal Wireless Users' Forum Workshop. Ruhl, M. K., and Antonishek, T. **100**(*1*), 71 (1995).

S

Sauter, G.

1993 Intercomparison of Photometric Units Maintained at NIST (USA) and PTB (Germany). Ohno, Y., and Sauter, G. **100**(*3*), 227 (1995).

Schima, F. J.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

Seiler, D. G.

International Workshop on Semiconductor Characterization: Present Status and Future Needs. Seiler, D. G., and Shaffner, T. J. **100**(*6*), 711 (1995).

Shaffner, T. J.

International Workshop on Semiconductor Characterization: Present Status and Future Needs. Seiler, D. G., and Shaffner, T. J. **100**(*6*), 711 (1995).

Smith, D. R.

Low-Temperature Properties of Silver. Smith, D. R., and Fickett, F. R. **100**(*2*), 119 (1995).

Smith, J. H.

Microform Calibration Uncertainties of Rockwell Diamond Indenters. Song, J. F., Rudder, F. F., Jr., Vorburger, T. V., and Smith, J. H. **100**(*5*), 543 (1995).

Smith, M. V.

Determination of the Transmittance Uniformity of Optical Filter Standard Reference Materials. Travis, J. C., Winchester, N. K., and Smith, M. V. **100**(*3*), 241 (1995).

Sobolewski, M. A.

Current and Voltage Measurements in the Gaseous Electronics Conference RF Reference Cell. Sobolewski, M. A. **100**(*4*), 341 (1995).

Song, J. F.

Microform Calibration Uncertainties of Rockwell Diamond Indenters. Song, J. F., Rudder, F. F., Jr., Vorburger, T. V., and Smith, J. H. **100**(*5*), 543 (1995).

Soniker, J.

Reactive Ion Etching in the Gaseous Electronics Conference RF Reference Cell. Brake, M. L., Pender, J. T. P., Buie, M. J., Ricci, A., Soniker, J., Pochan, P. D., and Miller, P. A. **100**(*4*), 441 (1995).

Sugar, J.

Analysis of the $(5d^2+5d6s) - 5d6p$ Transition Arrays of Os VII and Ir VIII, and the $6s\ ^2S - 6p\ ^2P$ Transitions of Ir IX. van het Hof, G. J., Joshi, Y. N., Wyart, J. F., and Sugar, J. **100**(*6*), 687 (1995).

T

Thomas, J. W. L.

Preparation and Calibration of Carrier-Free ^{209}Po Solution Standards. Collé, R., Lin, Z., Schima, F. J., Hodge, P. A., Thomas, J. W. L., Hutchinson, J. M. R., and Coursey, B. M. **100**(*1*), 1 (1995).

Thompson, A.

Spectral Radiance of a Large-Area Integrating Sphere Source. Walker, J. H., and Thompson, A. **100**(*1*), 37 (1995).

Tison, S. A.

Workshop on Water: Its Measurement and Control in Vacuum. Tison, S. A., and Looney, J. P. **100**(*1*), 75 (1995).

Travis, J. C.

Determination of the Transmittance Uniformity of Optical Filter Standard Reference Materials. Travis, J. C., Winchester, N. K., and Smith, M. V. **100**(*3*), 241 (1995).

V

Van Brunt, R. J.

Studies of Ion Kinetic-Energy Distributions in the Gaseous Electronics Conference RF Reference Cell. Olthoff, J. K., Van Brunt, R. J., and Radovanov, S. B. **100**(*4*), 383 (1995).

Forty-Seventh Annual Gaseous Electronics Conference. Van Brunt, R. J., and Gallagher, J. W. **100**(*4*), 495 (1995).

van het Hof, G. J.

Analysis of the $(5d^2+5d6s) - 5d6p$ Transition Arrays of Os VII and Ir VIII, and the $6s\ ^2S - 6p\ ^2P$ Transitions of Ir IX. van het Hof, G. J., Joshi, Y. N., Wyart, J. F., and Sugar, J. **100**(*6*), 687 (1995).

Vorburger, T. V.

Microform Calibration Uncertainties of Rockwell Diamond Indenters. Song, J. F., Rudder, F. F., Jr., Vorburger, T. V., and Smith, J. H. **100**(*5*), 543 (1995).

W

Walker, J. H.

Spectral Radiance of a Large-Area Integrating Sphere Source. Walker, J. H., and Thompson, A. **100**(*1*), 37 (1995).

Wallace, D. R.

COMPASS '95 Tenth Annual Conference on Computer Assurance. Danner, B. P., Ippolito, L. M., and Wallace, D. R. **100**(*5*), 601 (1995).

Wheeler, N. S.

Microstructural Characterization of Cobalt-Tungsten Coated Graphite Fibers. Wheeler, N. S. **100**(*6*), 641 (1995).

Winchester, N. K.

Determination of the Transmittance Uniformity of Optical Filter Standard Reference Materials. Travis, J. C., Winchester, N. K., and Smith, M. V. **100**(*3*), 241 (1995).

Wu, Y. C.

Low Electrolytic Conductivity Standards. Wu, Y. C., and Berezansky, P. A. **100**(*5*), 521 (1995).

Wyart, J. F.

Analysis of the $(5d^2+5d6s) - 5d6p$ Transition Arrays of Os VII and Ir VIII, and the $6s\ ^2S - 6p\ ^2P$ Transitions of Ir IX. van het Hof, G. J., Joshi, Y. N., Wyart, J. F., and Sugar, J. **100**(*6*), 687 (1995).

Y

Yang, A. J.-M.

Mixing Plate-Like and Rod-Like Molecules With Solvent: A Test of Flory-Huggins Lattice Statistics. Di Marzio, E. A., Yang, A. J.-M., and Glotzer, S. C. **100**(*2*), 173 (1995).

Yap, W. T.

On the Applications of Discontinuous Bessel Integrals to Chronoamperometry. Yap, W. T., and Durst, R. A. **100**(*1*), 61 (1995).

Yesha, Y.

Third International Conference on Information and Knowledge Management (CIKM-94). Fong, E., Hurwitz, S., and Yesha, Y. **100**(*1*), 67 (1995).